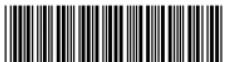


Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	110723664	BURKE ET AL.
Examiner		Art Unit
RICHARD CHAN		2618

SEARCHED

Class	Subclass	Date	Examiner
455	574, 552.1, 550.1, 572, 343.1	8/1/08	RC

SEARCH NOTES

Search Notes	Date	Examiner

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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